


<b>Search Notes</b> 	<b>Application/Control No.</b> 10533437	<b>Applicant(s)/Patent Under Reexamination</b> BECKER ET AL.
	<b>Examiner</b> Yuan L Chen	<b>Art Unit</b> 2854

SEARCHED			
Class	Subclass	Date	Examiner
101	185, 217, 285, 375, 376, 401.1, 480, 492	1/12-15/2009	yc

SEARCH NOTES		
Search Notes	Date	Examiner
limited text search (see search history)	1/12-15/2009	yc

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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